CENTRAL
TECHNOLOGIES

EMI

SURFACE MOUNT PRODUCT GUIDE

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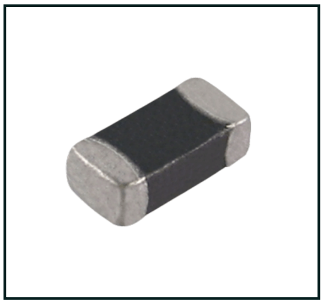


CTCB – Standard

Chip Beads – Multilayer

Description

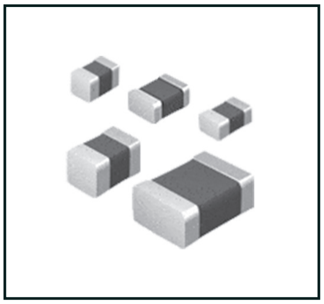
Standard multilayer ferrite chip beads

Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.
10 ~ 2200	100MHz (CTCB1206F-202S @ 30MHz; CTCB1206F-122S & -152S @ 50MHz)

DCR (Ω)	IDC	Size (mm)
0.025 ~ 0.95	100mA ~ 1000mA	0402 (1005), 0603 (1608), English (Metric)0805 (2012), 1206 (3216), 1210 (3225), 1806 (4516)



CTCB – Medium Current

Chip Beads – Multilayer

Description

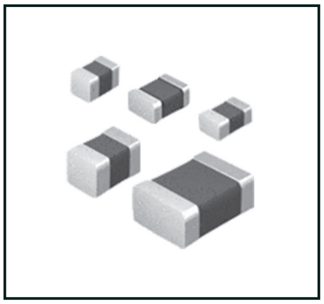
Medium current multilayer ferrite chip beads

Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
7 ~ 2000	100MHz		

DCR (Ω)	IDC	Size (mm)
0.06 ~ 0.70	150mA ~ 1000mA	0603 (1608), 0805 (2012), English (Metric)1206 (3216)



CTCB – High Speed

Chip Beads – Multilayer

Description

High speed multilayer ferrite chip beads

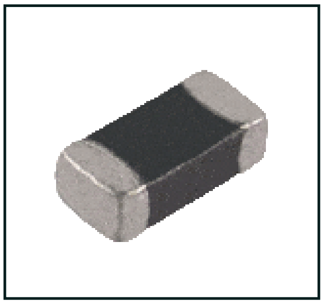
Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
6 ~ 120	100MHz		

DCR (Ω)	IDC	Size (mm)
0.3 ~ 0.7	400mA ~ 800mA	0603 (1608), 0805 (2012), English (Metric)1206 (3216)

EMI - SURFACE MOUNT



CTCB – Power

Chip Beads – Multilayer

Description

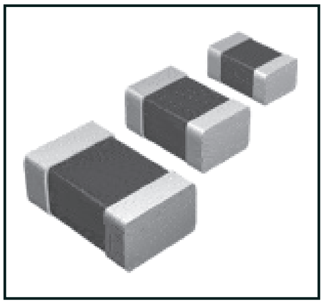
Power multilayer ferrite chip beads

Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
10 ~ 1500	100MHz (CTCB1206F-102P, 122P & 152P @ 50MHz)		

DCR (Ω)	IDC	Size (mm)
0.01 ~ 0.40	500mA ~ 6000mA	0402 (1005), 0603 (1608), English (Metric)0805 (2012), 1206 (3216), 1210 (3225), 1806 (4516), 1812 (4532)



CTCB – Ultra High Current

Chip Beads – Multilayer

Description

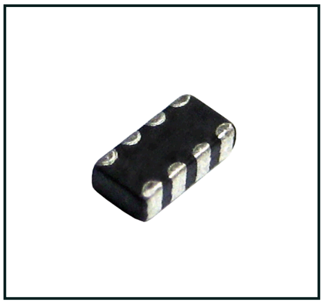
Ultra high current multilayer ferrite chip beads

Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
10 ~ 330	100MHz		

DCR (Ω)	IDC	Size (mm)
0.01 ~ 0.05	2000mA ~ 6000mA	0603 (1608), 0805 (2012), English (Metric)1206 (3216)



CTCBA1206F

Chip Beads – Multilayer

Description

Ferrite chip beads 4 line array

Application Use

Interfaces, notebook computers, LCD modules, portable electronics

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
30 ~ 1000	100MHz		

DCR (Ω)	IDC	Size (mm)
0.2 ~ 0.75	150mA ~ 500mA	1206 (3216), English (Metric)

EMI - SURFACE MOUNT

CT274

Chip Bead – Wire-wound

Description

SMD ferrite chips

Application Use

Noise suppression in computer peripherals, telecommunication equipment, data communication equipment and other consumer electronics.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
23 ~ 80	25MHz/100MHz		

DCR (Ω)	IDC	Size (mm)
0.6m ~ 0.9m		CT2743019447F (xx-0693019447F) = 5.1L x 3.05W x 2.85H CT2743021447F (xx-0693021447F) = 9.6L x 3.05W x 2.85H

CTACM

Wire-wound Common Mode / Filters

Description

SMD common mode chokes

Application Use

LAN's, telephones, personal computers, CD-ROM drives, electronic games.

Impedance (Ω)	Imp. Test Freq.	DCR (Ω)
225 ~ 1500	100MHz	0.004 ~ 0.015

Size (mm)
CTACM7060F (xx-473F-7060) = 7.0L x 6.0W x 4.0H CTACM8080F (xx-473F-8080) = 8.9L x 8.3W x 5.0H CTACM9070F (xx-473F-9070) = 9.0L x 7.0W x 5.0H CTACM1211F (xx-473F-1211) = 12.0L x 11.0W x 6.0H CTACM1513F (xx-473F-1513) = 15.0L x 13.0W x 6.0H

CTCMC0905F

Wire-wound Common Mode / Filters

Description

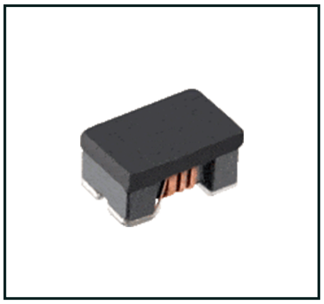
SMD common mode chokes

Application Use

LAN's, telephones, personal computers, CD-ROM drives, electronic games.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		10μH ~ 6500μH	10μH ~ 50μH @ 1.0kHz; 250μH ~ 6500μH @ 100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
0.08 ~ 1.05			9.2L x 6.0W x 5.0H



CTCM01F

Wire-wound Common Mode / Filters

Description

SMD common mode chokes

Application Use

USB line for personal computers and peripherals, IEEE 1394 line for personal computers, DVC, STB, LVDS, panel line for liquid display panels, graph cards.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
60 ~ 160	100MHz		

DCR (Ω)	IDC	Rated Current	Size (mm)
0.25 ~ 0.43	160mA ~ 300mA		1.25L x 1.00W x 0.8H

CTDLW5BF

Wire-wound Common Mode / Filters

Description

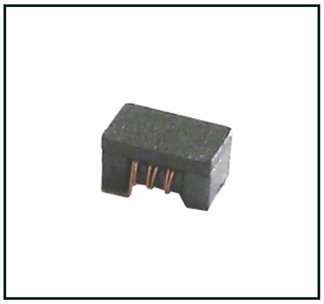
SMD common mode chokes

Application Use

Ideal for DC power lines in AC adapters of portable equipment.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
190 ~ 3000	100MHz		

DCR (Ω)	IDC	Rated Current	Size (mm)
0.02 ~ 0.30		0.5A ~ 5.0A	5.0L x 4.7W x 4.5H



CTDLW21SF

Wire-wound Common Mode / Filters

Description

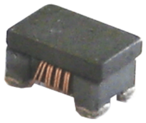
SMD common mode choke coils for signal lines

Application Use

Suitable for radiation noise suppression for any electronic devices. Used to counter common mode noise interference within high-speed signal lines. Applications like: USB2.0 line for personal computers and peripheral devices, IEEE1394 line for personal computers, DVC and LVDS panel link

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
30 ~ 370	100MHz		

DCR (Ω)	IDC	Rated Current	Size (mm)
0.20 ~ 0.45		280mA ~ 450mA	2.05L x 1.25W x 1.20H



CTDLW31SF

Wire-wound Common Mode / Filters

Description

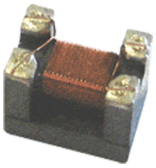
SMD common mode choke coils for signal lines

Application Use

Suitable for radiation noise suppression for any electronic devices. Used to counter common mode noise interference within high-speed signal lines. Applications like: USB2.0 line for personal computers and peripheral devices, IEEE1394 line for personal computers, DVC and LVDS panel link

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
90 ~ 600	100MHz		

DCR (Ω)	IDC	Rated Current	Size (mm)
0.30 ~ 0.80		260mA ~ 400mA	3.2L x 1.6W x 2.0H



CTDLW43SF

Wire-wound Common Mode / Filters

Description

SMD common mode chip inductors

Application Use

EMI suppression for data and signal lines, CAN Bus, telecom devices, consumer electronics

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		11µH ~ 100µH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
0.6 ~ 2.0	150mA ~ 250mA		4.5L x 3.2W x 2.8H

CTDR0904F

Wire-wound Common Mode / Filters

Description

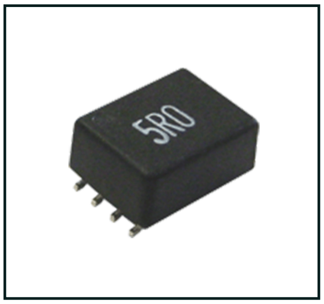
SMD data line chokes

Application Use

For the suppression of EMI in data and signal lines, e.g. CAN Bus

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		11µH ~ 4700µH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
0.10 ~ 0.70		0.2A ~ 0.5A	9.0L x 5.4W x 4.7H



CTDLFF

Wire-wound Common Mode / Filters

Description

SMD data line EMI filters

Application Use

LAN's, telephones, personal computers, electronic games.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		5.0μH	1.0MHz

DCR (Ω)	IDC	Rated Current	Size (mm)
0.20 ~ 0.25		0.1A ~ 0.5A	7.6L x 5.7W x 4.0H

CTMSRS1260F

Wire-wound Common Mode / Filters

Description

SMD shielded common mode choke

Application Use

Widely used in buck converters, flyback, SEPIC, laptops, network communication equipment

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		3.3μH ~ 1000μH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
			12.0L x 12.0W x 6.0H

CTMSRS1514F

Wire-wound Common Mode / Filters

Description

SMD shielded common mode choke

Application Use

Widely used in buck converters, flyback, SEPIC, laptops, network communication equipment

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		22μH ~ 1000μH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
			15.5L x 15.5W x 14.2H

CTDRQ125F

Wire-wound Common Mode / Filters

Description

SMD shielded dual wound inductor/transformer

Application Use

As a SEPIC or flyback transformer. As a buck, boost or coupled inductor. DC/DC converters. VRM inductor for CPU and DDR power supplies. Input and output filter chokes.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		0.47µH ~ 1000µH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)
			12.5L x 12.5W x 6.0H

CTDRQ127F

Wire-wound Common Mode / Filters

Description

SMD shielded dual wound inductor/transformer

Application Use

As a SEPIC or flyback transformer. As a buck, boost or coupled inductor. DC/DC converters. VRM inductor for CPU and DDR power supplies. Input and output filter chokes.

Impedance (Ω)	Imp. Test Freq.	Inductance	Ind. Test Freq
		0.47µH ~ 1000µH	100kHz

DCR (Ω)	IDC	Rated Current	Size (mm)